Amendments to the Specification:

Please add the following new paragraph header after paragraph [0001] ending on line 2 of page 1A of the specification as filed and before paragraph [0002] starting on line 1 of page 1B of the specification as filed:

Field of the Invention:

Please add the following new paragraph header after paragraph [0002] ending on line 4 of page 1B of the specification as filed and before paragraph [0003] starting on line 5 of page 1B of the specification as filed

Background of the Invention:

Please add the following new paragraph header after paragraph [0011] ending on line 2 of page 3 of the specification as filed and before paragraph [0012] starting on line 3 of page 3 of the specification as filed:

Objects and Summary of the Invention:

Please add the following <u>new paragraph header</u> after paragraph [0031] ending on line 18 of page 6 of the specification as filed and before paragraph [0032] beginning on line 19 of page 6 of the specification as filed:

Brief Description of the Drawings:

Please add the following <u>new paragraph header</u> after paragraph [0032] ending on line 12 of page 7 of the specification as filed and before paragraph [0033] beginning on line 13 of page 7 of the specification as filed:

Detailed Description:

Please replace the abstract with the following amended abstract:

The present invention concerns a system 10 using optical time-domain reflectometry (OTDR) to test a plurality of optic fibre lines 13 in a telecommunications network, more particularly suited to tree topology networks of PON type (Passive Optical Network). Said system comprises a plurality of fibre optic lines 13, a coupler 7 having one input and a plurality of outputs, each of said outputs being connected to one line of said plurality of lines 13, said system 10 being characterized in that it comprises means 14 for separating each of said lines 13 into two channels: a first channel 18 to receive a first test impulse corresponds to a first test and a second channel 19 to receive a second test impulse corresponding to a second test, the length of said second channel being greater than the length of said first channel by a predetermined overlength 15, each of said overlengths 15 being different for each of said lines 13.

~~Figure to be published: Figure 2~~

4